

Serial No. 09/929,047

IN THE SPECIFICATION:

The specification as amended below with replacement paragraphs showing added text with underlining and deleted text with ~~striethrough~~.

Please REPLACE the paragraph beginning at page 8, line 25 and continuing at page 9, line 1, with the following paragraph:

Fig. 2 is an illustration showing a model of a wiring pattern 10 to be analyzed by a high-frequency-corresponding simulation apparatus. In Fig. 2, a wiring pattern 12 and a wiring pattern 15 are illustrated in parallel. A driver 11D and a receiver 11R are set to ~~the~~ both ends of the wiring pattern 12. The driver 11D transmits a signal through the wiring pattern 12. The receiver 11R receives the signal.

Please REPLACE the paragraph beginning at page 12, line 1, with the following paragraph:

Moreover, the high-frequency-corresponding simulation apparatus realizes the RLC parallel wiring models are shown by the RLC parallel wiring model format 33 shown in Fig. 4C. Xaaaa denotes a call statement. [D-ed Node1] corresponds to one node No. of a line segment of the wiring pattern 31. [D-ed Node2] corresponds to the other node No. of the line segment of the wiring pattern 31. [D-ing Node1] corresponds to one node No. of a line-line segment of the wiring pattern 32. [D-ing Node2] corresponds to the other node No. of the line segment of the wiring pattern 32.

Please REPLACE the paragraph beginning at page 27, line 23 and continuing at page 28, line 1, with the following paragraph:

As described above, according to the present invention, when the total resistance value corresponding to a plurality of elements is equal to or larger than a first threshold value, an analysis is executed in accordance with a mixed model obtained by using a high-frequency element having a small high-frequency-element delay causing analysis time to increase as a RLC model and high-frequency elements other than the high-frequency element having a small high-frequency-element delay as high-frequency element models. Therefore, an advantage is obtained that it is possible to decrease the analysis time corresponding to a high frequency.